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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

ln re U	S.S. Patent Application of	<i>)</i>)
HASE	GAWA et al.)) Unit 2813
Applic	ation Number: 10/058,787)) Examiner
Filed:	January 30, 2002) Dolan, Jennifer M
For:	SEMICONDUCTOR INTEGRATED CIRCUIT DEVICE, METHOD OF TESTING SEMICONDUCTOR INTEGRATED CIRCUIT DEVICE AND METHOD OF MANUFACTURING SEMICONDUCTOR INTEGRATED CIRCUIT DEVICE)
ATTO	RNEY DOCKET NO. ASAM.0038)

Honorable Assistant Commissioner for Patents Washington, D.C. 20231

COVER LETTER

Sir:

[x] The fee for submission of claims is calculated as shown below:

For	TOTAL WITH NEW CLAIMS ADDED	TOTAL CURRENTLY ON FILE	CLAIMS PAID	RATE	CALCULATION
Total Claims	10	12	(Over 20)	x \$18	0
Independent Claims	3	3	(Over 3)	x \$86	0
MULTIPLE DEPENDENT CLAIM(S)				+ \$290	0
REDUCTION FOR F	ILING BY SMALL ENTITY RIFIED STATEMENT MUS	(note 37 C.F.R. §§ 1.9, 1.2 TET BE ATTACHED	7, 1.28).	x 1/2	
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In addition, the below-identified communications are submitted in the above-captioned application or proceeding:

[x] Response to Office Action	[] Petition for Extension of Time (month)		
(with Claim Amendments)	[] Terminal Disclaimer		
Substitute Specification & marked-up copy	Letter to Draftsperson w/ sheets of drawings		
Preliminary Amendment	[] Assignment		
Other	Petition under		

[]	Please charge my Deposit Account Number in the amount of to cover the fees for A duplicate copy of this paper is enclosed.		
[]	A check in the amount of \$ to cover the fee is enclosed.		
[x]	[x] The Commissioner is hereby authorized to charge any additional fees associated with this communic or credit any overpayment to Deposit Account Number 08-1480 .		
	Respectfully submitted,		
	Stanley P. Fisher Registration Number 24,344 Yuan Carlos A. Marquez Registration No. 34,072		

REED SMITH LLP 3110 Fairview Park Drive Suite 1400 Falls Church, Virginia 22042 (703) 641-4200 March 15, 2004 MAR 1 5 2004 ST

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

s In re U	J.S. Patent Application of)	
HASE	GAWA et al.)) ·	Art Unit 2813
Applic	ation Number: 10/058,787))	Examiner
Filed:	January 30, 2002))	Dolan, Jennifer M
For:	SEMICONDUCTOR INTEGRATED CIRCUIT DEVICE, METHOD OF TESTING SEMICONDUCTOR INTEGRATED CIRCUIT DEVICE AND METHOD OF MANUFACTURING SEMICONDUCTOR INTEGRATED CIRCUIT DEVICE)	
	ney Docket No. ASAM.0038)	
Hono	rable Assistant Commissioner		

Honorable Assistant Commissioner for Patents
Washington, D.C. 20231

RESPONSE AND AMENDMENT UNDER 37 C.F.R. § 1.111

Sir:

This is in response to the Office Action dated December 17, 2003, the period for response to which expires on March 17, 2004. Please amend the above-identified application as follows: